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FORM PTO-14497 & TRADEMARKS. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DKT NO. 4700-083 (467.4)	SERIAL NO. 10/051,201
INFORMATION DISCLOSURE STATEMENT BY APPLICANT		APPLICANT Linus G. Fonkwe et al.	
		FILING DATE January 18, 2002	GROUP 1615

## **U.S. PATENT DOCUMENTS**

## **FOREIGN PATENT DOCUMENTS**

**OTHER DOCUMENTS (Incl. Author, Title, Date, Pertinent pages, etc.)**

EXAMINER 	DATE CONSIDERED <u>6/9/05</u>
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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**U.S. PATENT DOCUMENTS**

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CL.	SUBCL.	FILING DATE IF APPROP.
GK	CC	5,962,053	10/1999	Merritt, II	426	93	
	DD	6,331,205	12/2001	Paris et al.	106	205.9	
	EE	6,340,473	1/2002	Tanner et al.	424	451	6/30/2000
	FF	6,375,981	4/2002	Gilleland et al.	424	452	6/1/2002
	GG	6,517,865	2/2003	Cade et al.	424	451	
	HH	6,528,088	3/2003	Gilleland et al.	424	451	
	II	6,582,727	6/2003	Tanner et al.	424	451	
	JJ	6,745,546	6/2004	Tanner et al.	53	560	
	KK	6,790,495	9/2004	Tomka et al.	428	35.2	
GK	LL	US 2002/0155200	10/2002	Macquarie	426	250	

**FOREIGN PATENT DOCUMENTS**

		DOCUMENT NO.	DATE	COUNTRY	CL.	SUBCL.	TRANSLATION	
							YES	NO
GK	MM	EP 1,216,680	6/2002	Europe	—	—	X	
GK	NN	EP 1,258,242	11/2002	Europe	—	—	X Considered English Abstr	
GK	OO	EP 1,103,254	5/2001	Europe	—	—	X	
GK	PP	WO 02/053088	7/2002	WIPO	—	—	X Considered English Abstr	
GK	QQ	WO 02/07711	1/2002	WIPO	—	—	X Considered English Abstr	
GK	RR	WO 02/49572	6/2002	WIPO	—	—	X Considered English Abstr	

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G.K. Krizler	6/9/05

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EXAMINER	G.Krishna	DATE CONSIDERED	6/9/05
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		DOCUMENT NO.	DATE	COUNTRY	CL.	SUBCL	TRANSLATION	
							YES	NO
CK	ZZ	JP 4089841	3/1992	Japan			abstract	
	AAA	JP 50105767	8/1975	Japan			abstract	
	BBB	JP 50105766	8/1975	Japan			abstract	
	CCC	EP 0328317	8/1989	Europe				
	DDD	JP 63118229	5/1988	Japan			abstract	
CK	EEE	JP 3127945	5/1991	Japan			abstract	

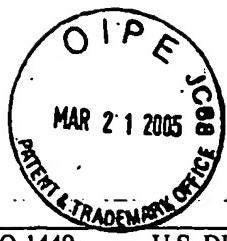
**OTHER DOCUMENTS** (Incl. Author, Title, Date, Pertinent pages, etc.)

EXAMINER	<u>G. Kozieck</u>	DATE CONSIDERED	<u>6/9/01</u>
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GK	FFF	JP 3190709	8/1991	Japan			abstract	
GK	GGG	JP 2000127225	5/2000	Japan			abstract	
GK	HHH	JP 3121825	5/1991	Japan			abstract	
GK	III	CA 2243227	5/1999	Canada				
GK	JJJ	JP 7062160	3/1995	Japan			abstract	

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